S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/664,762	WOO ET AL.	
Examiner	Art Unit	_
Vincent T. Tran	2115	

	SEAR	CHED	
Class	Subclass	Date	Examiner
713	100	11/21/2005	VT
711	105	11/21/2005	VT
711	159	11/21/2005	VT
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH (INCLUDING SEAR)
	DATE	EXMR
EAST - see attachment	11/21/2005	VT
EAST - see attachment	11/22/2005	Vī
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